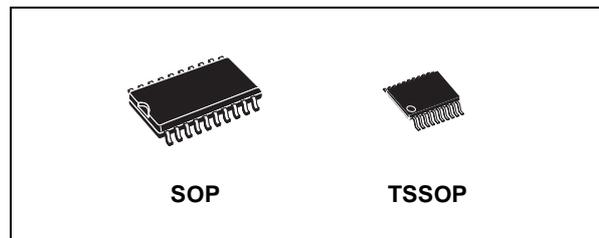




74VHC573

OCTAL D-TYPE LATCH WITH 3 STATE OUTPUTS NON INVERTING

- HIGH SPEED: $t_{PD} = 5.0 \text{ ns}$ (TYP.) at $V_{CC} = 5V$
- LOW POWER DISSIPATION:
 $I_{CC} = 4 \mu\text{A}$ (MAX.) at $T_A = 25^\circ\text{C}$
- HIGH NOISE IMMUNITY:
 $V_{NIH} = V_{NIL} = 28\% V_{CC}$ (MIN.)
- POWER DOWN PROTECTION ON INPUTS
- SYMMETRICAL OUTPUT IMPEDANCE:
 $|I_{OH}| = I_{OL} = 8 \text{ mA}$ (MIN)
- BALANCED PROPAGATION DELAYS:
 $t_{PLH} \approx t_{PHL}$
- OPERATING VOLTAGE RANGE:
 $V_{CC}(\text{OPR}) = 2V \text{ to } 5.5V$
- PIN AND FUNCTION COMPATIBLE WITH 74 SERIES 573
- IMPROVED LATCH-UP IMMUNITY
- LOW NOISE: $V_{OLP} = 0.9V$ (MAX.)



ORDER CODES

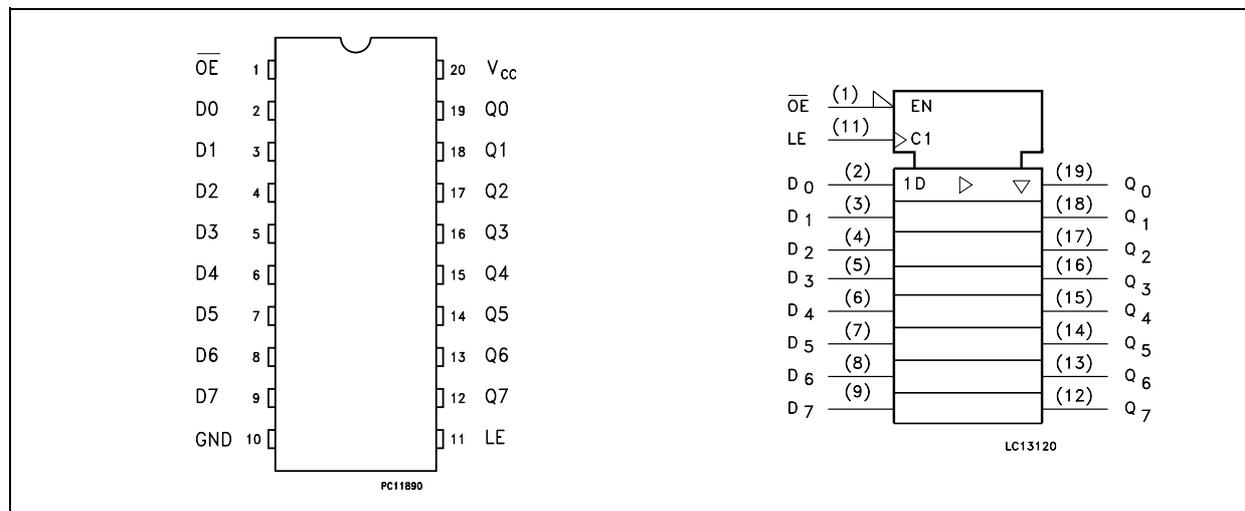
PACKAGE	TUBE	T & R
SOP	74VHC573M	74VHC573MTR
TSSOP		74VHC573TTR

DESCRIPTION

The 74VHC573 is an advanced high-speed CMOS OCTAL D-TYPE LATCH with 3 STATE OUTPUTS NON INVERTING fabricated with sub-micron silicon gate and double-layer metal wiring C²MOS technology. These 8 bit D-Type latch are controlled by a latch enable input (LE) and an output enable input (\overline{OE}). While the LE inputs is held at a high level, the Q outputs will follow the data input precisely. When the LE is taken low, the Q outputs will be latched

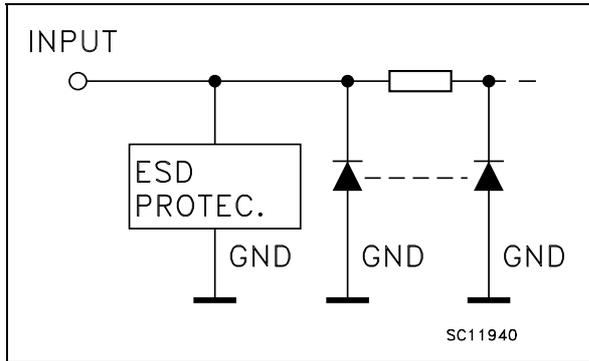
precisely at the logic level of D input data. While the (\overline{OE}) input is low, the 8 outputs will be in a normal logic state (high or low logic level) and while (\overline{OE}) is in high level, the outputs will be in a high impedance state. Power down protection is provided on all inputs and 0 to 7V can be accepted on inputs with no regard to the supply voltage. This device can be used to interface 5V to 3V. All inputs and outputs are equipped with protection circuits against static discharge, giving them 2KV ESD immunity and transient excess voltage.

PIN CONNECTION AND IEC LOGIC SYMBOLS



74VHC573

INPUT EQUIVALENT CIRCUIT



PIN DESCRIPTION

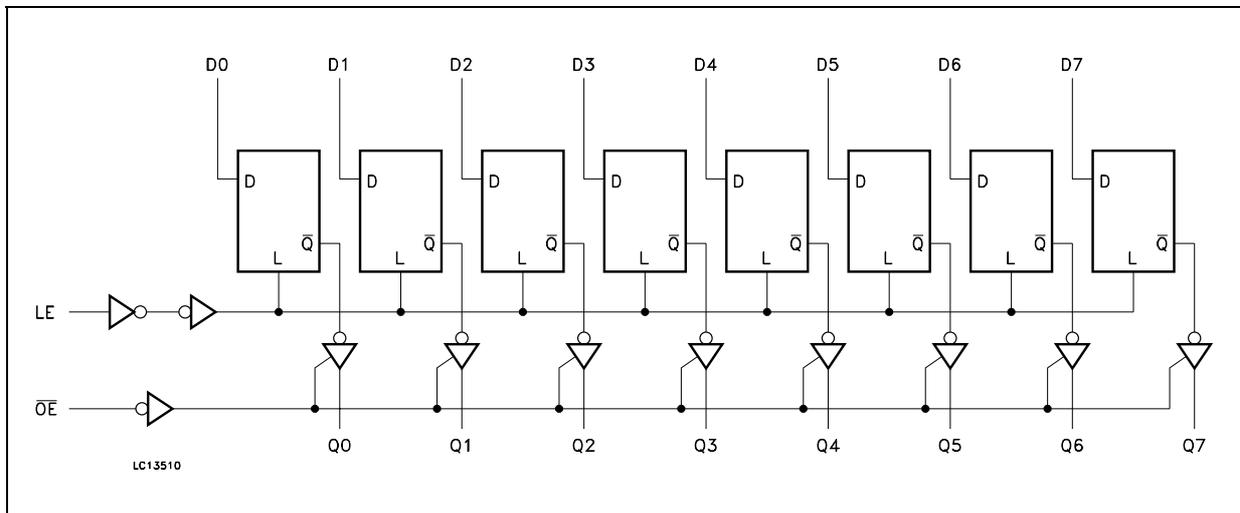
PIN No	SYMBOL	NAME AND FUNCTION
1	\overline{OE}	3 State Output Enable Input (Active LOW)
2, 3, 4, 5, 6, 7, 8, 9	D0 to D7	Data Inputs
12, 13, 14, 15, 16, 17, 18, 19	Q0 to Q7	3-State Latch Outputs
11	LE	Latch Enable Input
10	GND	Ground (0V)
20	V _{CC}	Positive Supply Voltage

TRUTH TABLE

INPUTS			OUTPUT
\overline{OE}	LE	D	Q
H	X	X	Z
L	L	X	NO CHANGE*
L	H	L	L
L	H	H	H

X : Don't Care
 Z : High Impedance
 * : Q Outputs are Latched at the time when the LE input is taken low logic level

LOGIC DIAGRAM



This logic diagram has not been used to estimate propagation delays

ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V_{CC}	Supply Voltage	-0.5 to +7.0	V
V_I	DC Input Voltage	-0.5 to +7.0	V
V_O	DC Output Voltage	-0.5 to $V_{CC} + 0.5$	V
I_{IK}	DC Input Diode Current	- 20	mA
I_{OK}	DC Output Diode Current	± 20	mA
I_O	DC Output Current	± 25	mA
I_{CC} or I_{GND}	DC V_{CC} or Ground Current	± 75	mA
T_{stg}	Storage Temperature	-65 to +150	$^{\circ}C$
T_L	Lead Temperature (10 sec)	300	$^{\circ}C$

Absolute Maximum Ratings are those values beyond which damage to the device may occur. Functional operation under these conditions is not implied.

RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter	Value	Unit
V_{CC}	Supply Voltage	2 to 5.5	V
V_I	Input Voltage	0 to 5.5	V
V_O	Output Voltage	0 to V_{CC}	V
T_{op}	Operating Temperature	-55 to 125	$^{\circ}C$
dt/dv	Input Rise and Fall Time (note 1) ($V_{CC} = 3.3 \pm 0.3V$) ($V_{CC} = 5.0 \pm 0.5V$)	0 to 100 0 to 20	ns/V

1) V_{IN} from 30% to 70% of V_{CC}

DC SPECIFICATIONS

Symbol	Parameter	Test Condition		Value						Unit	
		V _{CC} (V)		T _A = 25°C			-40 to 85°C		-55 to 125°C		
				Min.	Typ.	Max.	Min.	Max.	Min.		Max.
V _{IH}	High Level Input Voltage	2.0		1.5			1.5		1.5		V
		3.0 to 5.5		0.7V _{CC}			0.7V _{CC}		0.7V _{CC}		
V _{IL}	Low Level Input Voltage	2.0				0.5		0.5		0.5	V
		3.0 to 5.5				0.3V _{CC}		0.3V _{CC}		0.3V _{CC}	
V _{OH}	High Level Output Voltage	2.0	I _O =-50 μA	1.9	2.0		1.9		1.9		V
		3.0	I _O =-50 μA	2.9	3.0		2.9		2.9		
		4.5	I _O =-50 μA	4.4	4.5		4.4		4.4		
		3.0	I _O =-4 mA	2.58			2.48		2.4		
		4.5	I _O =-8 mA	3.94			3.8		3.7		
V _{OL}	Low Level Output Voltage	2.0	I _O =50 μA		0.0	0.1		0.1		0.1	V
		3.0	I _O =50 μA		0.0	0.1		0.1		0.1	
		4.5	I _O =50 μA		0.0	0.1		0.1		0.1	
		3.0	I _O =4 mA			0.36		0.44		0.55	
		4.5	I _O =8 mA			0.36		0.44		0.55	
I _{oz}	High Impedance Output Leakage Current	5.5	V _I = V _{IH} or V _{IL} V _O = V _{CC} or GND			±0.25		± 2.5		± 2.5	μA
I _I	Input Leakage Current	0 to 5.5	V _I = 5.5V or GND			± 0.1		± 1		± 1	μA
I _{CC}	Quiescent Supply Current	5.5	V _I = V _{CC} or GND			4		40		40	μA

AC ELECTRICAL CHARACTERISTICS (Input $t_r = t_f = 3\text{ns}$)

Symbol	Parameter	Test Condition			Value						Unit	
		V_{CC} (V)	C_L (pF)		$T_A = 25^\circ\text{C}$			-40 to 85°C		-55 to 125°C		
					Min.	Typ.	Max.	Min.	Max.	Min.		Max.
t_{PLH} t_{PHL}	Propagation Delay Time LE to Q	3.3(*)	15			7.6	11.9	1.0	14.0	1.0	14.0	ns
		3.3(**)	50			10.1	15.4	1.0	17.5	1.0	17.5	
		5.0(**)	15			5.0	7.7	1.0	9.0	1.0	9.0	
		5.0(**)	50			6.5	9.7	1.0	11.0	1.0	11.0	
t_{PLH} t_{PHL}	Propagation Delay Time D to Q	3.3(*)	15			7.0	11.0	1.0	13.0	1.0	13.0	ns
		3.3(**)	50			9.5	14.5	1.0	16.5	1.0	16.5	
		5.0(**)	15			4.5	6.8	1.0	8.0	1.0	8.0	
		5.0(**)	50			6.0	8.8	1.0	10.0	1.0	10.0	
t_{PZL} t_{PZH}	Output Enable Time	3.3(*)	15	$R_L = 1\text{K}\Omega$		7.3	11.5	1.0	13.5	1.0	13.5	ns
		3.3(**)	50	$R_L = 1\text{K}\Omega$		9.8	15.0	1.0	17.0	1.0	17.0	ns
		5.0(**)	15	$R_L = 1\text{K}\Omega$		5.2	7.7	1.0	9.0	1.0	9.0	ns
		5.0(**)	50	$R_L = 1\text{K}\Omega$		6.7	9.7	1.0	11.0	1.0	11.0	ns
t_{PLZ} t_{PHZ}	Output Disable Time	3.3(*)	50	$R_L = 1\text{K}\Omega$		10.7	14.5	1.0	16.5	1.0	16.5	ns
		5.0(**)	50	$R_L = 1\text{K}\Omega$		6.7	9.7	1.0	11	1.0	11	
t_w	Pulse Width (LE) HIGH	3.3(*)				5.0		5.0		5.0	ns	
		5.0(**)				5.0		5.0		5.0		
t_s	Setup Time D to LE HIGH or LOW	3.3(*)				3.5		3.5		3.5	ns	
		5.0(**)				3.5		3.5		3.5		
t_h	Setup Time D to LE HIGH or LOW	3.3(*)				1.5		1.5		1.5	ns	
		5.0(**)				1.5		1.5		1.5		
t_{OSLH} t_{OSHL}	Output to Output Skew time (note 1)	3.3(*)	50			1.5		1.5		1.5	ns	
		5.0(**)	50			1.0		1.0		1.0		

(*) Voltage range is $3.3\text{V} \pm 0.3\text{V}$ (**) Voltage range is $5.0\text{V} \pm 0.5\text{V}$ Note 1 : Parameter guaranteed by design. $t_{soLH} = |t_{pLHm} - t_{pLHn}|$; $t_{soHL} = |t_{pHLm} - t_{pHLn}|$

CAPACITIVE CHARACTERISTICS

Symbol	Parameter	Test Condition			Value						Unit	
					$T_A = 25^\circ\text{C}$			-40 to 85°C		-55 to 125°C		
					Min.	Typ.	Max.	Min.	Max.	Min.		Max.
C_{IN}	Input Capacitance					8	10		10		10	pF
C_{OUT}	Output Capacitance					10						pF
C_{PD}	Power Dissipation Capacitance (note 1)					29						pF

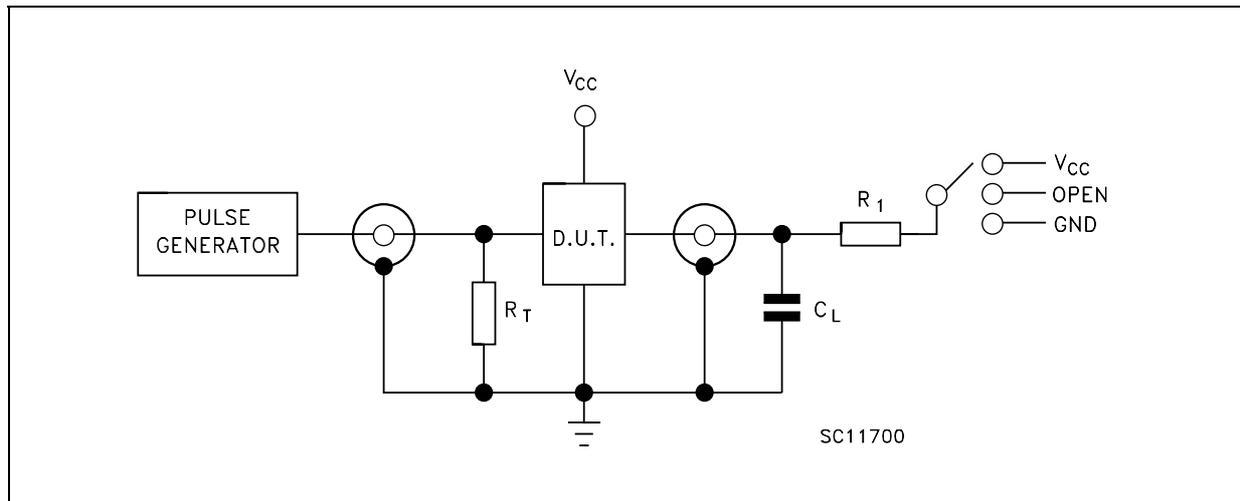
1) C_{PD} is defined as the value of the IC's internal equivalent capacitance which is calculated from the operating current consumption without load. (Refer to Test Circuit). Average operating current can be obtained by the following equation. $I_{CC(opr)} = C_{PD} \times V_{CC} \times f_{IN} + I_{CC}/8$ (per Latch)

DYNAMIC SWITCHING CHARACTERISTICS

Symbol	Parameter	Test Condition		Value						Unit	
		V _{CC} (V)		T _A = 25°C			-40 to 85°C		-55 to 125°C		
				Min.	Typ.	Max.	Min.	Max.	Min.		Max.
V _{OLP}	Dynamic Low Voltage Quiet Output (note 1, 2)	5.0	C _L = 50 pF		0.6	0.9					V
V _{OLV}				-0.9	-0.6						
V _{IHD}	Dynamic High Voltage Input (note 1, 3)	5.0		3.5						V	
V _{ILD}	Dynamic Low Voltage Input (note 1, 3)	5.0				1.5				V	

- 1) Worst case package.
- 2) Max number of outputs defined as (n). Data inputs are driven 0V to 5.0V, (n-1) outputs switching and one output at GND.
- 3) Max number of data inputs (n) switching. (n-1) switching 0V to 5.0V. Inputs under test switching: 5.0V to threshold (V_{ILD}), 0V to threshold (V_{IHD}), f=1MHz.

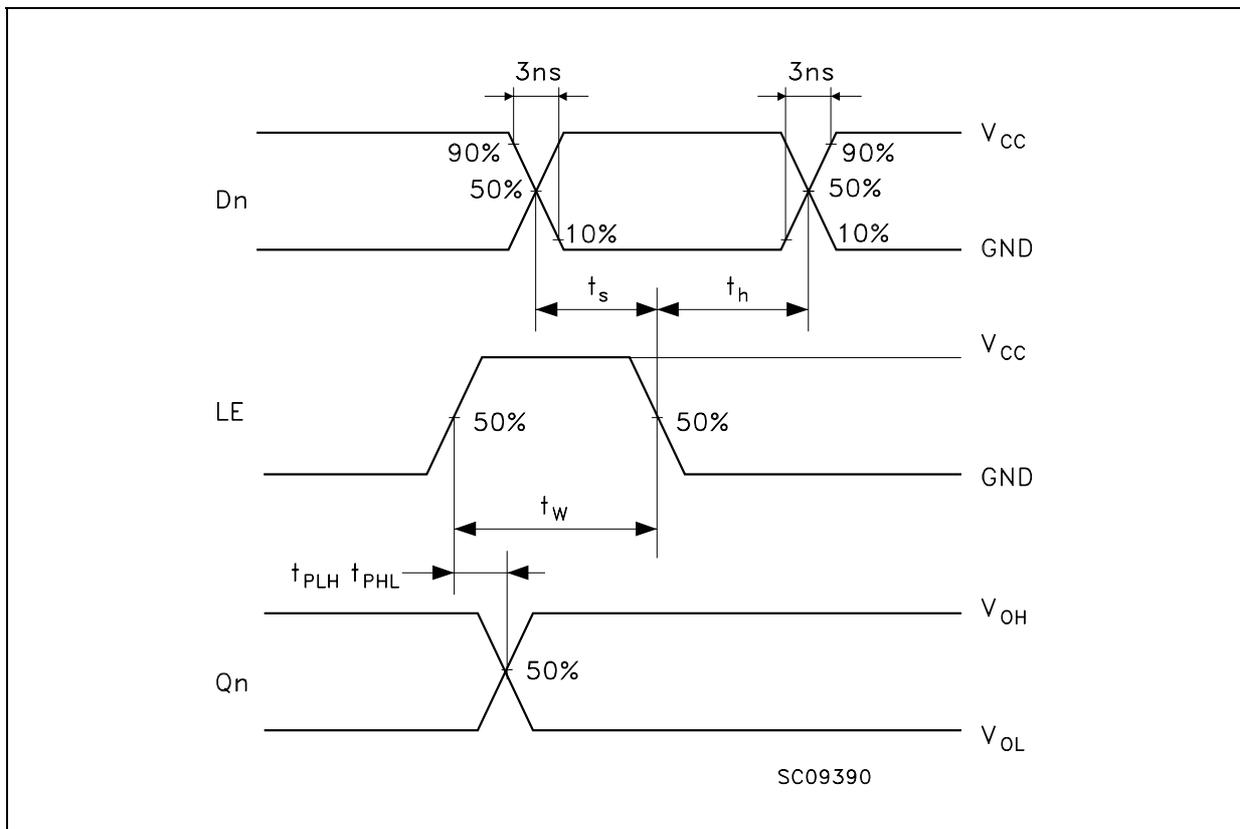
TEST CIRCUIT



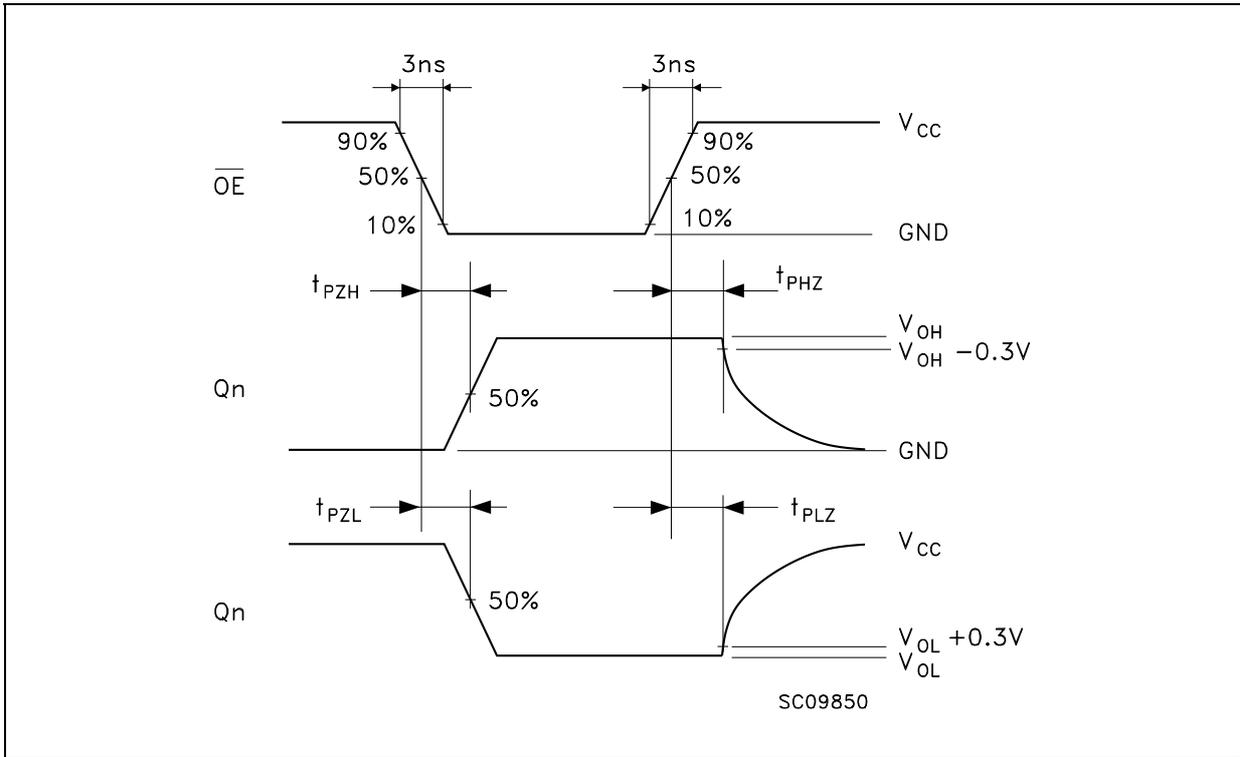
TEST	SWITCH
t _{PLH} , t _{PHL}	Open
t _{PZL} , t _{PLZ}	V _{CC}
t _{PZH} , t _{PHZ}	GND

C_L = 15/50pF or equivalent (includes jig and probe capacitance)
 R_L = R₁ = 1KΩ or equivalent
 R_T = Z_{OUT} of pulse generator (typically 50Ω)

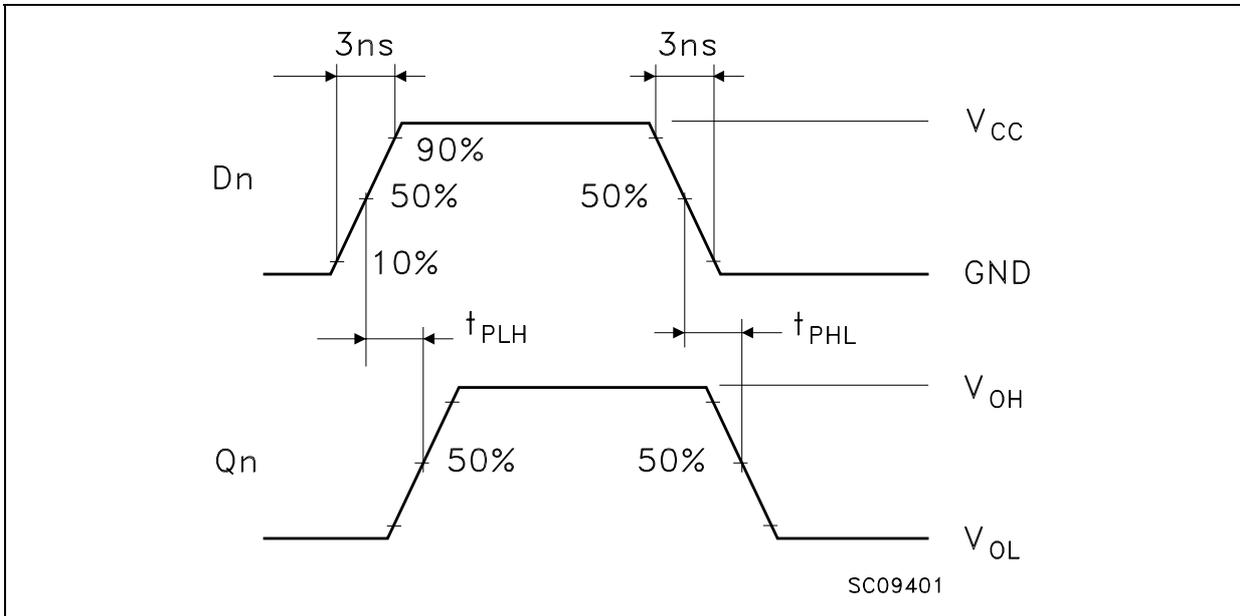
WAVEFORM 1: LE TO Qn PROPAGATION DELAYS, LE MINIMUM PULSE WIDTH, Dn TO LE SETUP AND HOLD TIMES (f=1MHz; 50% duty cycle)



WAVEFORM 2: OUTPUT ENABLE AND DISABLE TIMES (f=1MHz; 50% duty cycle)

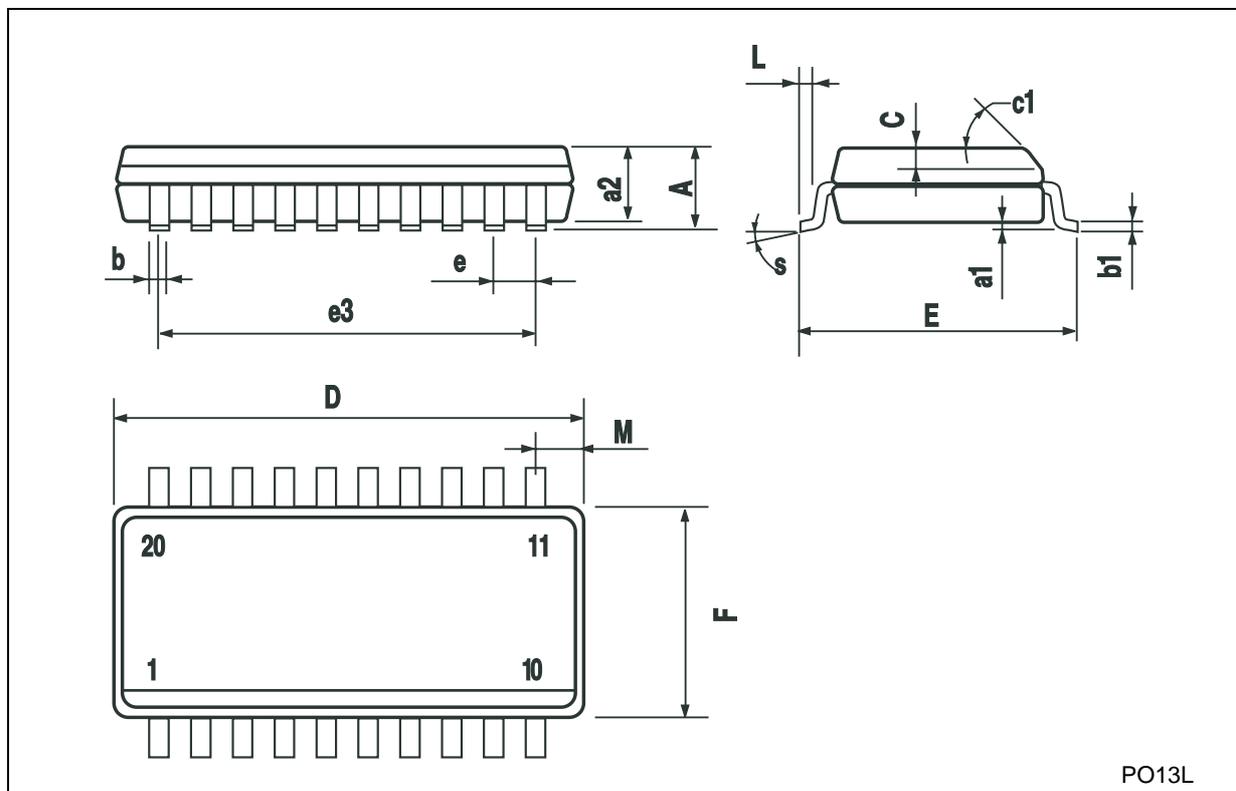


WAVEFORM 3: PROPAGATION DELAY TIME (f=1MHz; 50% duty cycle)



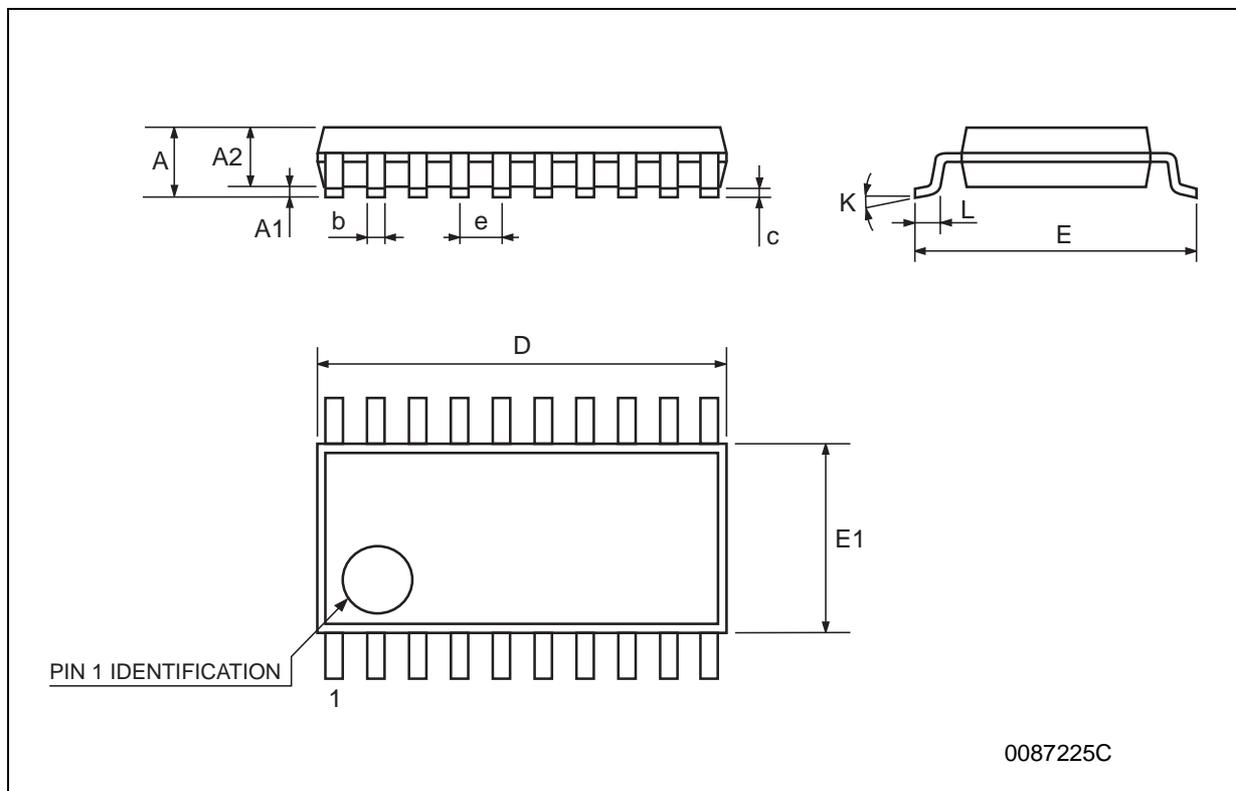
SO-20 MECHANICAL DATA

DIM.	mm.			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A			2.65			0.104
a1	0.1		0.2	0.004		0.008
a2			2.45			0.096
b	0.35		0.49	0.014		0.019
b1	0.23		0.32	0.009		0.012
C		0.5			0.020	
c1	45° (typ.)					
D	12.60		13.00	0.496		0.512
E	10.00		10.65	0.393		0.419
e		1.27			0.050	
e3		11.43			0.450	
F	7.40		7.60	0.291		0.300
L	0.50		1.27	0.020		0.050
M			0.75			0.029
S	8° (max.)					



TSSOP20 MECHANICAL DATA

DIM.	mm.			inch		
	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
A			1.2			0.047
A1	0.05		0.15	0.002	0.004	0.006
A2	0.8	1	1.05	0.031	0.039	0.041
b	0.19		0.30	0.007		0.012
c	0.09		0.20	0.004		0.0079
D	6.4	6.5	6.6	0.252	0.256	0.260
E	6.2	6.4	6.6	0.244	0.252	0.260
E1	4.3	4.4	4.48	0.169	0.173	0.176
e		0.65 BSC			0.0256 BSC	
K	0°		8°	0°		8°
L	0.45	0.60	0.75	0.018	0.024	0.030



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